SCAS234B - JULY 1990 - REVISED OCTOBER 1996

- Members of the Texas Instruments Widebus™ Family
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- Flow-Through Architecture Optimizes PCB Layout
- Distributed V<sub>CC</sub> and GND Pin Configuration Minimizes High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Package Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Pin Spacings

### description

The 'AC16240 are 16-bit buffers and line drivers designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

They can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. These devices provide inverting outputs and symmetrical active-low output-enable ( $\overline{OE}$ ) inputs.

10E 48 20E 47 🛮 1A1 1Y1 2 1Y2 46 ¶ 1A2 GND 4 45 GND 1Y3 5 44**∏** 1A3 1Y4 43 🛮 1A4 6 42 🛛 V<sub>CC</sub> 7  $V_{CC}$ 2Y1 41 2A1 8 2Y2 9 40 2A2 GND 39 GND 10 38**∏** 2A3 2Y3 11 37 2A4 2Y4 12 3Y1 13 36 3A1

35 3A2

34 GND

33 🛮 3A3

**54AC16240...WD PACKAGE** 

**74AC16240...DL PACKAGE** 

(TOP VIEW)

3Y4 32 **1** 3A4 17 18 31 V<sub>CC</sub>  $V_{CC}$ 30 **1** 4A1 4Y1 19 29**[**] 4A2 4Y2 20 GND 28 | GND 21 27 🛮 4A3 4Y3 22 4Y4 26**∏** 4A4 23 25 3OE 4OE 24

3Y2

GND

3Y3

14

**II** 16

The 74AC16240 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed circuit board area.

The 54AC16240 is characterized for operation over the full military temperature range of -55°C to 125°C.

The 74AC16240 is characterized for operation from -40°C to 85°C.

### FUNCTION TABLE (each 4-bit buffer)

INP	JTS	OUTPUT
ŌĒ	Α	Y
L	Н	L
L	L	Н
Н	X	Z

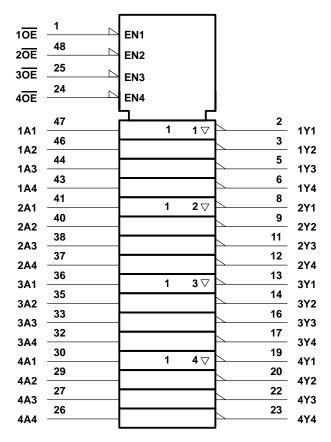


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TEXAS INSTRUMENTS

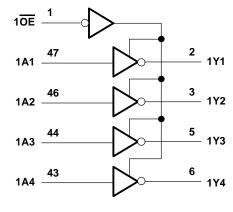
### logic symbol†

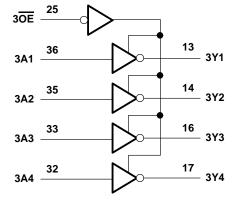


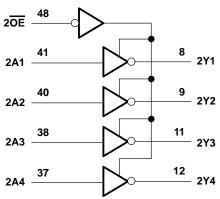
<sup>&</sup>lt;sup>†</sup>This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

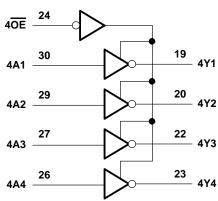


### logic diagram (positive logic)









### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	-0.5 V to V <sub>CC</sub> + 0.5 V
Output voltage range, V <sub>O</sub> (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	±50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±50 mA
Continuous current through V <sub>CC</sub> or GND	±400 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air)(see Note 2): DL package .	1.2 W
Storage temperature range, T <sub>Stq</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



<sup>2.</sup> The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

### recommended operating conditions (see Note 3)

			54	54AC16240		74	AC1624	0	LINIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		3	5	5.5	3	5	5.5	V	
		V <sub>CC</sub> = 3 V	2.1			2.1				
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			3.15			V	
		V <sub>CC</sub> = 5.5 V	3.85			3.85				
		VCC = 3 V			0.9			0.9		
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 4.5 V			1.35			1.35		
		V <sub>CC</sub> = 5.5 V		A P	1.65		-	1.65		
VI	Input voltage		0	Q	VCC	0		VCC	V	
٧o	Output voltage		0	,C,	VCC	0		VCC	V	
		VCC = 3 V	4	2	-4			-4		
lOH	High-level output current	V <sub>CC</sub> = 4.5 V	BA	,	-24			-24	mA	
		V <sub>CC</sub> = 5.5 V			-24			-24		
		V <sub>CC</sub> = 3 V			12			12		
lOL	Low-level output current	V <sub>CC</sub> = 4.5 V			24			24	mA	
		V <sub>CC</sub> = 5.5 V			24			24		
Δt/Δν	Input transition rise or fall rate		0		10	0		10	ns/V	
TA	Operating free-air temperature		-55		125	-40		85	°C	

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		T <sub>A</sub> = 25°C			54AC1	6240	74AC1	LINIT	
PARAMETER		VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		3 V	2.9			2.9		2.9		
	I <sub>OH</sub> = -50 μA	4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
Voн	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.48		2.48		V
		4.5 V	3.94			3.8		3.8		
	I <sub>OH</sub> = -24 mA	5.5 V	4.94			4.8	EM	4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85	EV	3.85		
		3 V			0.1	4	0.1		0.1	
	$I_{OL} = 50 \mu A$ $I_{OL} = 12 mA$ $I_{OL} = 24 mA$	4.5 V			0.1	ζ <sub>)</sub>	0.1		0.1	
		5.5 V			0.1	$\gamma_{Q_i}$	0.1		0.1	
VOL		3 V			0.36	) V	0.44		0.44	V
		4.5 V			0.36	1	0.44		0.44	
	10L - 24 111A	5.5 V			0.36		0.44		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65		1.65	
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1		±1	μΑ
loz	V <sub>O</sub> = V <sub>CC</sub> or GND	5.5 V			±0.5		±5		±5	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80		80	μΑ
C <sub>i</sub>	$V_I = V_{CC}$ or GND	5 V		4.5						pF
Co	$V_O = V_{CC}$ or GND	5 V		12						pF

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



SCAS234B - JULY 1990 - REVISED OCTOBER 1996

## switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	4 = 25°C	;	54AC1	6240	74AC1	6240	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>PLH</sub>	А	V	1.8	5.4	7.5	1.8	8.3	1.8	8.3	ns
t <sub>PHL</sub>	A	ī	2.5	7	9.3	2.5	10.2	2.5	10.2	115
<sup>t</sup> PZH	ŌĒ	V	2.1	6.1	8.5	2.1	9.5	2.1	9.5	no
<sup>t</sup> PZL	OE	ī	2.9	8.4	11.3	2.9	12.6	2.9	12.6	ns
<sup>t</sup> PHZ	ŌĒ	V	4.3	6.2	8.3	4.3	8.7	4.3	8.7	no
t <sub>PLZ</sub>	OE .	r	3.6	6	7.8	3.6	8.4	3.6	8.4	ns

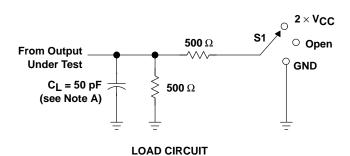
# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	4 = 25°C	;	54AC1	6240	74AC1	6240	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
<sup>t</sup> PLH	А	V	1.3	3.3	5.3	1.3	5.8	1.3	5.8	20
t <sub>PHL</sub>	A	ī	1.9	4.3	6.5	1.9	7.1	1.9	7.1	ns
<sup>t</sup> PZH	1	V	1.6	3.8	5.9	1.6	6.6	1.6	6.6	20
<sup>t</sup> PZL	ŌĒ	ī	3.2	4.7	7.2	3.2	8.1	3.2	8.1	ns
<sup>t</sup> PHZ	ŌĒ	V	4.2	6	7.7	4.2	8.1	4.2	8.1	
t <sub>PLZ</sub>	OE	Ť	3.4	5.1	6.9	3.4	7.3	3.4	7.3	ns

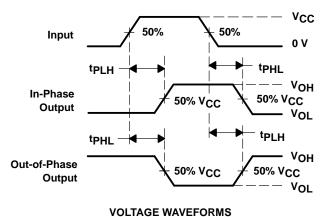
### operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

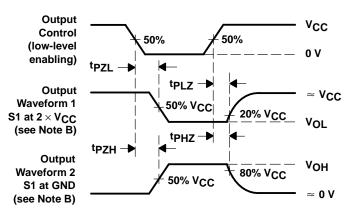
	PARAMETER			TEST CONDITIONS		
C . Down discinction conscitones not letch		Outputs enabled	C <sub>1</sub> = 50 pF. f = 1 MHz		42	pF
Cpd	Power dissipation capacitance per latch	Outputs disabled	$C_L = 50 \text{ pF},$	f = 1 MHz	6	рг

### PARAMETER MEASUREMENT INFORMATION



TEST	S1				
tPLH/tPHL	Open				
tPLZ/tPZL	2×V <sub>CC</sub>				
tPHZ/tPZH	GND				





**VOLTAGE WAVEFORMS** 

NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f = 3 \ ns$ ,  $t_f = 3 \ ns$ .
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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